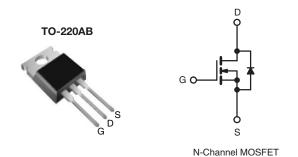


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	500				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0.85				
Q _g (Max.) (nC)	38				
Q _{gs} (nC)	9.0				
Q _{gd} (nC)	18				
Configuration	Single				



FEATURES

• Low Gate Charge Qq Results in Simple Drive



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective Coss Specified
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Two Transistor Forward
- Half Bridge
- Full Bridge

ORDERING INFORMATION	
Package	TO-220AB
Lead (Pb)-free	IRF840APbF
	SiHF840A-E3
SnPb	IRF840A
	SiHF840A

ABSOLUTE MAXIMUM RATINGS ($T_{\mathbb{C}}$	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500	V	
Gate-Source Voltage			V_{GS}	± 30	V	
Ocalia de Paris Ocasal	\/ at 10 \/	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		8.0	А	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	5.1		
Pulsed Drain Current ^a			I _{DM}	32		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	510	mJ	
Repetitive Avalanche Current ^a			I _{AR}	8.0	А	
Repetitive Avalanche Energy ^a			E _{AR}	13	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 16 mH, R_q = 25 Ω , I_{AS} = 8.0 A (see fig. 12).
- c. $I_{SD} \le 8.0$ A, $dI/dt \le 100$ A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0			

PARAMETER	SYMBOL	TEST (MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	V, I _D = 250 μA	500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I _D = 1 mA	-	0.58	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_0$	_{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	V _{GS} = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 50$	$00 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	25	μΑ
2010 date voltage Brain Garrent	1088	$V_{DS} = 400 \text{ V}, \text{ V}$	_{GS} = 0 V, T _J = 125 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4.8 A ^b	-	-	0.85	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 50$	$0 \text{ V}, I_D = 4.8 \text{ A}^b$	3.7	-	-	S
Dynamic							
Input Capacitance	C_{iss}	V	_{GS} = 0 V,	-	1018	-	
Output Capacitance	C _{oss}	$V_{DS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. } 5$		-	155	-	pF
Reverse Transfer Capacitance	C _{rss}			-	8.0	-	
Output Capacitance	C _{oss}	V _{GS} = 0 V; V _{DS} = 1.0 V, f = 1.0 MHz			1490		
Output Capacitance	C _{oss}	V _{GS} = 0 V; V _{DS} = 400 V, f = 1.0 MHz			42		
Effective Output Capacitance	C _{oss} eff.	V _{GS} = 0 V; V _{DS} = 0 V to 400 V ^c			56		
Total Gate Charge	Q_g			-	-	38	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V	$I_D = 8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	9.0	
Gate-Drain Charge	Q_{gd}			-	-	18	
Turn-On Delay Time	t _{d(on)}				11	-	
Rise Time	t _r	$V_{DD} = 2$	250 V, I _D = 8 A	-	23	-]
Turn-Off Delay Time	t _{d(off)}	$R_g = 9.1 \Omega, R_I$	$R_g = 9.1 \Omega$, $R_D = 31 \Omega$, see fig. 10^b		26	-	ns -
Fall Time	t _f	1		-	19	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	8.0	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	32	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V ^b		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 8 A, dl/dt = 100 A/μs ^b		-	422	633	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.16	3.24	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

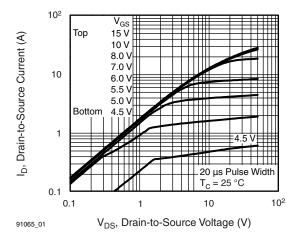


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

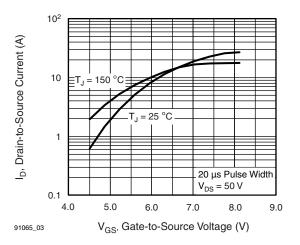


Fig. 3 - Typical Transfer Characteristics

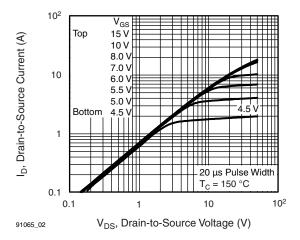


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

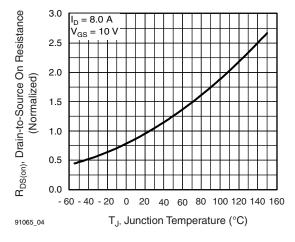


Fig. 4 - Normalized On-Resistance vs. Temperature



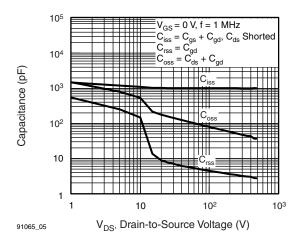


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

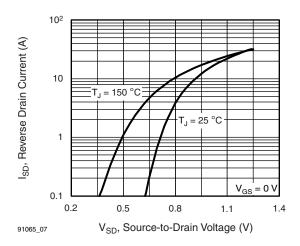


Fig. 7 - Typical Source-Drain Diode Forward Voltage

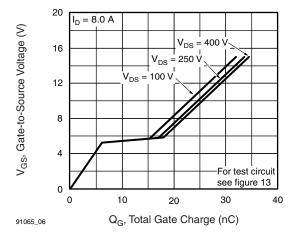


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

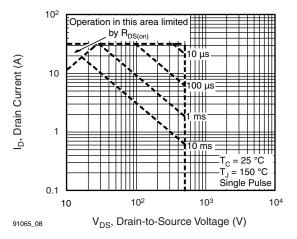


Fig. 8 - Maximum Safe Operating Area





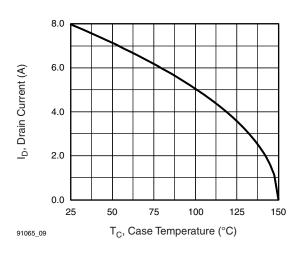


Fig. 9 - Maximum Drain Current vs. Case Temperature

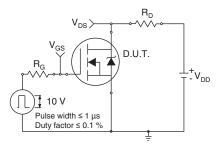


Fig. 10a - Switching Time Test Circuit

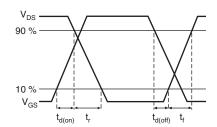


Fig. 10b - Switching Time Waveforms

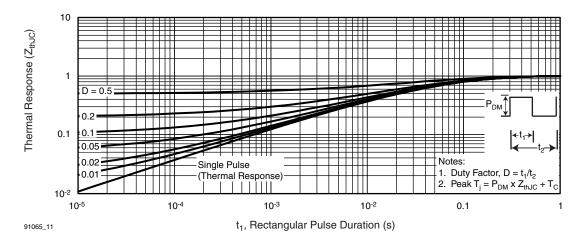


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



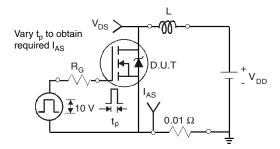


Fig. 12a - Unclamped Inductive Test Circuit

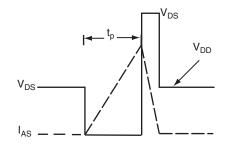


Fig. 12b - Unclamped Inductive Waveforms

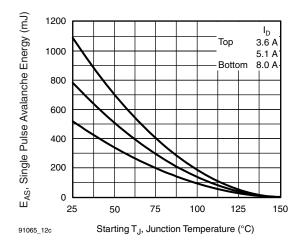


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

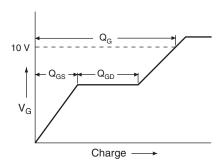


Fig. 12d - Basic Gate Charge Waveform

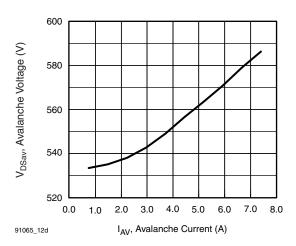


Fig. 13a - Typical Drain-to-Source Voltage vs.
Avalanche Current

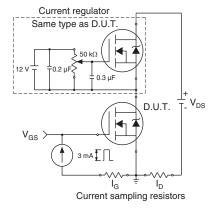
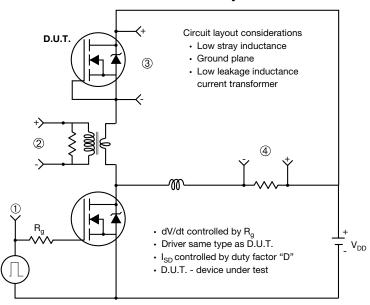


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



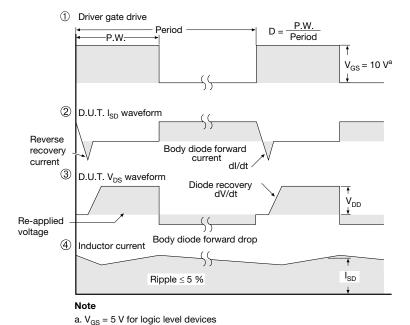


Fig. 14 - For N-Channel

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TO-220-1



DIM.	MILLIM	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.24	4.65	0.167	0.183		
b	0.69	1.02	0.027	0.040		
b(1)	1.14	1.78	0.045	0.070		
С	0.36	0.61	0.014	0.024		
D	14.33	15.85	0.564	0.624		
Е	9.96	10.52	0.392	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.10	6.71	0.240	0.264		
J(1)	2.41	2.92	0.095	0.115		
L	13.36	14.40	0.526	0.567		
L(1)	3.33	4.04	0.131	0.159		
ØР	3.53	3.94	0.139	0.155		
Q	2.54	3.00	0.100	0.118		
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031						

Note

 M* = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



Revison: 14-Dec-15 1 Document Number: 66542



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